Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/705,386	LIU ET AL.	
Examiner	Art Unit	
Thien F. Tran	2811	

SEARCHED			
Class	Subclass	Date	Examiner
257	690, 713 734, 737 738, 778	2/9/2006	т
257	782-784	2/9/2006	П
		. <u> </u>	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NO (INCLUDING SEARCH	TES STRATEGY	)
	DATE	EXMR
Search history printout	2/9/2006	π